



Introduction

H series is a high-end comprehensive manual test probe configuration, the device has excellent stability and maneuverability, and the test precision are higher than that of the rest of the industry brand, unique pneumatic chuck mobile technology, flexible UPStart modular structure design, enhance sexual shock system, these are all SEMISHARE advanced innovation technology advantage in the industry. At the same time, the equipment can support late expansion and upgrading, to meet the needs of customers for a variety of test applications, the equipment is very suitable for R & D center and major university laboratories step budget acquisition investment.

Application Direction

Wafer I-V/C-V test, RF/mmW test, MEMS, Hall test, HIGH-voltage/high-current test, LD/LED/PD test, PCB/package device test, in-chip circuit/electrode /PAD test, etc

Product Feature

- Ergonomic design, operation more human
- Solid and stable platform frame structure
- Easy operation and fast start, reduce the time of equipment training
- UPStart modular structure, equipment support late expansion and upgrade
- The chuck moving platform is driven by large handle differential head for comfortable operation
- TMCS product customization based on UPStart module
- Three - stage lifting needle base platform
- Design of stiffened metal frame structure
- Microscope air - controlled lifting control
- Air floating self-balancing shock table
- Chuck Air bearing move TM
- Loadable laser

Specification

Model	SH-6	SH-8	SH-12
Dimension	L 820mm*W 720mm*H 890mm	L 960mm*W 850mm*H 900mm	L 1300mm*W 920mm*H 920mm
Weight (about)	170KG	230KG	300KG
Electricity Demand	220VC, 50~60Hz		
Chuck	Size & Rotation angle	6", 360° Rotation	8", 360° Rotation
	X-Y Travel range	6" * 6"	8" * 8"
	Moving resolution	1µm	
	Sample fixed mode	Vacuum adsorption	
	Electrical design	Electrical Floating with Banana plug adapter, can be used as a backside electrode	
Platen	U shape platen	6 micropositioners available	8 micropositioners available
	Move range & adjustment mode	Platen can be quickly lifted up and down 6mm for fast probe tip separation Platen can be fine tuned up and down 25mm precisely with 1µm resolution	
Microscope	Travel range	X-Y axis : 2" * 2", Z axis : 50.8mm	
	Moving resolution	1µm	
	Switching object lens	Microscope tilting 30° manually by Lever	
	Magnification	20~4000X	
	Lens specification	Eyepiece: 10X ; Objective lens : 5X, 10X, 20X, 50X ,100X(option)	
Micropositioner specification	CCD pixels	50W (Analog) / 200W (Digital) / 500W (Digital)	
	X-Y-Z Travel range	12mm-12mm-12mm / 8mm-8mm-8mm	
	Mechanical resolution	10µm / 2µm / 0.7µm / 0.1µm	
	Current leakage accuracy	10pA / 100fA (with Shielding Box)	
Cable connectors	Banana head / Crocodile clip / Coaxial / Triaxial		
Application	Wafer test, Photoelectric device test, PCB / IC test, RF test, high voltage and high current measurement etc.		
Optional Accessories	Chuck quick roll out mechanism		
	Microscope tilt mechanism (Tilting 30° manually by Lever)		
	Microscope pneumatic lifting mechanism		
	Laser repair with cutting, ablation and welding function		
	Probe clamp		
	Dark field of microscope / DIC / Normarski test, Light intensity / wavelength test		
	IC hotspot detection by LC		
	High voltage and high current measurement		
	Hot chuck		
	High/Low temperature chuck		
	Shielding box		
	Special adapter		
	Vibration free table		
	Gold-plated chuck		
	Coaxial / Triaxial chuck		
	Chuck quick move-out and fine adjustment mechanism		
	Chuck rotation fine adjustment		
	Light intensity / wavelength testing		
	RF Testing		
Active probe			
Low current / Capacitance test			
Intergation of intergral sphere			
Fixture for Fibre optic coupler test			
Fixture of Package IC test			
Fixture of PCB test			
Special Custom design			